Application/Control No.	Applicant(s)/Patent under Reexamination
10/750,146	SHIH, WEI-YAN
Examiner	Art Unit
Richard Hanig	2873

	SEARCHED		
Class	Subclass	Date	Examiner
359	291 290 223	03/03/05	RH
	223		
	224		
	225		
	226		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
354	290	03/03/05	att
	223 224	,	
	226		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
D. Spector	03/02/05	RH
D. Spector 359/295, 29D		
223,224,225,226		
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